Influence of the Molecular Ordering on the Wetting of SiO₂/Air Interfaces by Alkanes

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Alkanes from 16 to 50 C atoms show three wetting topologies at SiO_2 /air interfaces. Below the bulk freezing temperature T_b , small crystallites (frozen droplets which can be annealed into mesas of uniform height) are observed. A monolayer of homeotropically oriented molecules covers the air/substrate interface in between. At T_b , the crystallites melt into droplets. The ordered monolayer remains up to $T_S^{SV} \approx T_b + 3$ °C, probably due to fluctuation-stabilized "surface freezing." Above T_S^{SV} , a liquid alkane film wets the surface. The decoupling of T_b and T_S^{SV} , and the difference between the ordered and liquid surface energies, causes the droplet-to-film transition. [S0031-9007(97)04693-0]

PACS numbers: 68.45.Gd, 68.55.Jk

Wetting is governed by interfacial interactions [1,2], which can efficiently be studied by the use of liquid hydrocarbons. Their interactions are dominated by long range dispersion forces which can be tuned by changing their conformation or chain length. Appropriate solid surfaces for wetting studies are chemically and physically well defined silicon wafer surfaces. With such systems, particularly, the contribution of long range dispersion forces has been investigated [3-5]. In general, however, wetting is determined by long and short range forces [6-8]. Even for alkanes, local interactions are explicit through surface freezing, i.e., the bulk liquid/vapor interface is covered with an ordered alkane monolayer up to several °C above the bulk melting temperature [9,10]. In the following, we will show that surface freezing of alkanes also occurs at solid/vapor interfaces and that it has a significant impact on the wetting behavior.

The alkanes $(C_n H_{2n+2} := C_n)$ were used as purchased [Aldrich, C_{50} and C_{60} from Fluka, purity >99% (C_{50} > 98%)]. Pieces of silicon wafers (Wacker Siltronic GmbH, Burghausen, oxide layer thickness $\approx 15 \text{ Å}$) served as substrates. The SiO₂ surfaces were prepared as described elsewhere [11]. Ultrathin alkane films were made with equivalent results by spincoating either from chloroform solutions or alkane melts. Deposition parameters were selected to deposit material sufficient for average surface coverages of several hundred Å. The samples were studied via reflection optical microscopy (Olympus AX70), x-ray reflectivity (Stoe Θ/Θ reflectometer), and ellipsometry (Beaglehole Instruments). The ellipsometry and x-ray data analysis is described elsewhere [10,12]. The homemade temperature stages (accuracy ≈0.1 °C) were calibrated with the alkane bulk melting temperatures, which were separately checked via differential scanning calorimetry to match literature values. Some experiments with short chain alkanes, performed under saturated alkane vapor atmosphere, show that evaporation losses do not affect the results.

For chain lengths C_{16} through C_{50} , optical microscopy studies reveal three different wetting topologies (Fig. 1) with transition temperatures at the bulk melting tempera-

ture $T_{\rm b}$ [13] and at $T_{\rm S}^{\rm SV}$, slightly above $T_{\rm b}$ (Fig. 2). For chain lengths below C₁₆ and above C₅₀, respectively, only the two topologies typical for $T < T_{\rm b}$ and $T > T_{\rm S}^{\rm SV}$ are observed.

Below $T_{\rm b}$, depending on the state of annealing, the crystalline material is clustered either as frozen droplets, as frozen droplets with pedestals of smooth, planar surfaces, or as mesalike crystallites (islands), which also have smooth, planar surfaces. The interference colors and atomic force microscopy data indicate that the mesas and pedestals have similar heights ($\approx 500 \text{ Å}$). Annealing at temperatures just below $T_{\rm b}$ induces the pedestals to grow in area at constant height. The alkane material is supplied from the center droplet, which decreases in size.

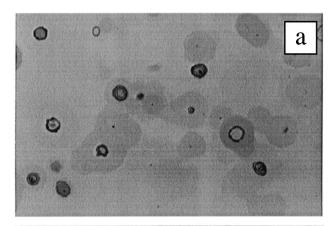
from the center droplet, which decreases in size. Between $T_{\rm b}$ and $T_{\rm S}^{\rm SV}$, droplets are observed (occasionally distorted by pinning, e.g., dust particles). Their interference colors vary continuously indicating smooth spherical caps. Evidently they are composed of liquid alkane, consistent with the microscopically observed melting behavior at $T_{\rm b}$. From the droplet diameter 2r and the number i of interference fringes $[h \approx i\lambda/2n, \lambda = 500 \text{ nm}, n = \text{refractive index} (1.45)]$, the contact angle $\Theta_{\rm d}$ can be estimated

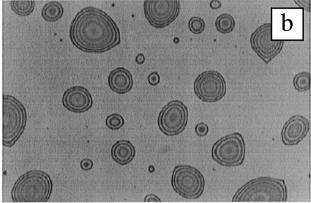
$$\Theta_{\rm d} = \sin^{-1} \left(\frac{2rh}{r^2 + h^2} \right). \tag{1}$$

 $\Theta_{\rm d}$ depends on the temperature. Roughly independent from the chain length, it decreases from $\approx 10^{\circ}$ near $T_{\rm b}$ to $\approx 2^{\circ}$ near $T_{\rm S}^{\rm SV}$ [14]. At constant temperature, $\Theta_{\rm d}$ does not change with time.

Above $T_{\rm S}^{\rm SV}$, we observe either structureless, smooth surfaces if only small amounts of material were deposited, or, with a higher alkane surface coverage, very flat droplets with noncircular, smoothly curved shapes. In the latter case, the contact angle is very small and the topology is very susceptible to distortion by pinning.

The analysis [12] of the x-ray reflectivity data (Fig. 3) reveals below $T_{\rm S}^{\rm SV}$ (i.e., in the mesa and in the droplet regime) thin films (electron density $\approx 0.31 \pm 0.03~e/{\rm \AA}^3$). These films are evident even without sophisticated analysis





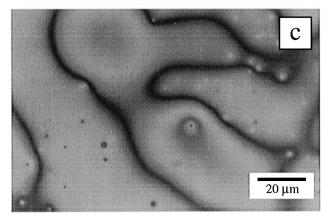


FIG. 1. Optical microscopy images of C_{30} in the three wetting topologies ($T_b = 66.1$ °C, $T_S^{SV} = 69.3$ °C). (a) T = 65.0 °C; (b) T = 68.0 °C; (c) T = 70.0 °C.

from the interference minima ("Kiessig fringes"). Their thicknesses scale with the alkane length. For $C_n < C_{30}$, they are slightly thicker ($\approx 10\%$) than one all-transmolecular length. For $C_n > C_{30}$, they roughly match the length. Detailed studies [14] reveal even/odd effects and minor thickness changes at T_b . All of this indicates that the films consist of densely packed ("frozen") alkanes, oriented normal to the interface, which will, henceforth, be termed "monolayers." These monolayers are at the SiO_2 /air interface. The mesas, which are much thicker, do not contribute to the monolayer interferences [15] and

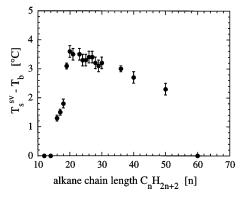
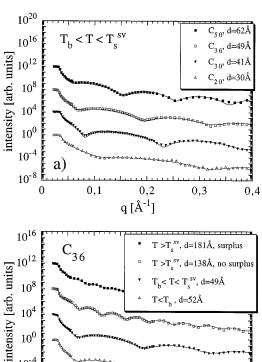


FIG. 2. Difference between the droplet/film transition temperature $T_{\rm S}^{\rm SV}$ and the bulk freezing temperature $T_{\rm b}$ as a function of the alkane chain length.

the liquid droplets do not produce interferences at all due to their curved surfaces.

Above $T_{\rm S}^{\rm SV}$, x-ray interferences also reveal smooth films. If the amount of deposited material is sufficient only for films of less than ≈ 160 Å thickness, the sample surface appears smooth under the microscope. Reflectivity shows films with thicknesses roughly proportional to the amount of deposited material. With more deposited



10⁴
10⁻⁸
10⁻⁸
b)
10⁻⁸
0 0,1 0,2 0,3 0,4
q [Å⁻¹]

FIG. 3. X-ray reflectivity data $(q=4\pi/\lambda \sin \Theta)$, $\Theta=$ grazing angle, $\lambda=1.54$ Å) of (a) alkanes of various chain lengths at $T_{\rm b} < T < T_{\rm S}^{\rm SV}$ and (b) C_{36} on SiO₂ at various temperatures. The solid lines show fits from which the layer thicknesses are derived.

material, microscopy reveals the accumulation of the "surplus" of material beyond 160-200 Å film thickness in very flat droplets. X-ray reflectivity still reveals a spacing of 160-200 Å. This probably originates from a film between the flat droplets because the interferences disappear with increasing droplet coverage. The film consists of liquid alkane because its thickness is independent from the alkane chain length, no x-ray interferences due to any internal molecular layering are observed, and because of its electron density $(0.24 \pm 0.03 \ e/\text{Å}^3)$. The film is also apparent from optical microscopy observations. Upon cooling below $T_{\rm S}^{\rm SV}$, droplets are formed even from smooth films thinner than 160 Å, or, in the surplus case, in the areas between the flat droplets.

The topologies are reversible (except for the transformation of the frozen droplets into mesas). Upon cooling, temperature hysteresis is observed. Upon heating, no hysteresis is found ($T_{\rm b}$ and $T_{\rm S}^{\rm SV}$ are defined in heating experiments). Temperature variation within the various wetting regimes does not change their general wetting topologies.

Scattering and interference effects spoiled ellipsometric studies with spincoated films. Therefore, adsorption experiments from saturated vapor phases were performed with C_{20} . These resulted in smooth films. Figure 4 shows that their ellipticity, which is roughly proportional to the adsorbed amount [10], changes abruptly at $T_{\rm S}^{\rm SV}$. No changes are detected at $T_{\rm b}$. Below $T_{\rm S}^{\rm SV}$, both the ellipsometric data and the x-ray reflectivity measurements (*from the same samples*) reveal a film thickness comparable to that of monolayers of spincoated samples. Above $T_{\rm S}^{\rm SV}$, within a wide temperature range, the layer thickness is constantly about half a molecular length (\approx 15 Å). The discrepancy to the 160–200 Å films measured with x-rays on spincoated samples is tentatively attributed to an incomplete saturation of the vapor phase in the adsorption experiment.

The various experimental results show a change in the wetting behavior at T_b and T_S^{SV} . At the bulk freezing

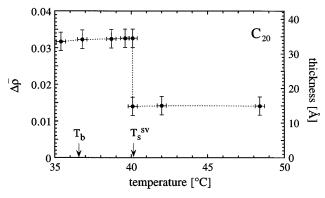


FIG. 4. Ellipsometric data from adsorption experiments of C_{20} onto SiO_2 (stepwise temperature increase, equilibrium data). $\Delta \bar{\rho}$ is the difference in ellipticity between bare and coated surfaces. The thicknesses are calculated with an assumed isotropic refractive index of 1.45.

temperature $T_{\rm b}$, this can be expected. However, to the best of our knowledge, the bulk properties do not change abruptly at $T_{\rm S}^{\rm SV}$. Hence, it is suggested that the wetting transition at $T_{\rm S}^{\rm SV}$ is due to a discontinuity in the interfacial molecular ordering.

The chain length and temperature dependency of $T_{\rm S}^{\rm SV}$ resembles that of the surface freezing temperature of alkane monolayers at bulk alkane/air interfaces $T_{\rm S}^{\rm LV}$ [9,10]. However, $T_{\rm S}^{\rm LV}$ is on average 0.3–0.5 °C lower than $T_{\rm S}^{\rm SV}$, and $\gamma^{\rm LV}$ does not change discontinuously at $T_{\rm S}^{\rm LV}$ or $T_{\rm S}^{\rm SV}$ (see inset in Fig. 5). Hence, surface freezing at the droplet/air interface is not causing the transition. On the other hand, a discontinuous change of the molecular ordering at the bulk alkane/substrate interface at $T_{\rm S}^{\rm SV}$ (i.e., of $\gamma^{\rm SL}$) cannot be excluded with any degree of certainty, because neither x-ray reflectivity nor microscopy provided information on the molecular ordering at this interface in the droplet or film regime. Nevertheless, the x-ray and ellipsometric measurements prove an abrupt change of the molecular ordering at the air/substrate interface exactly at $T_{\rm S}^{\rm SV}$ suggesting a change in $\gamma^{\rm SV}$ as a major cause of the transition.

Equilibrium presumed, we may write

$$\gamma_f^{SV} = \gamma_f^{LV} \cos \Theta_f + \gamma_f^{SL};
\gamma_d^{SV} = \gamma_d^{LV} \cos \Theta_d + \gamma_d^{SL}.$$
(2)

SV, LV, SL, d, and f label the various interfaces between solid (S), air (vapor = V), and liquid (L) phases, respectively, droplet (d), and film (f) regimes. According to the

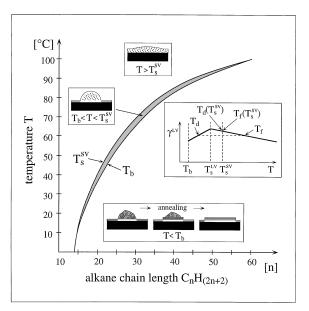


FIG. 5. Wetting regimes, topologies, and suggested molecular orderings as a function of the temperature and the chain length. The inset shows a schematic of the change of the surface tension γ^{LV} with temperature [9] including an example of $T_{\rm f}$ and $T_{\rm d}$ which matches Eq. (3) and the specific pair $T_{\rm d}(T_{\rm S}^{\rm SV})$ and $T_{\rm f}(T_{\rm S}^{\rm SV})$ to calculate $\Delta \gamma_{\rm f,d}^{\rm SV}(T_{\rm S}^{\rm SV})$. White fillings of interfaces indicate uncertainties in the molecular ordering.

literature [9], $\gamma^{\rm LV}$ varies with temperature near $T_{\rm S}^{\rm SV}$ as shown in the inset of Fig. 5. From that is evident that corresponding temperatures $T_{\rm d}$ and $T_{\rm f}$ below and above $T_{\rm S}^{\rm LV}$ can be found so that

$$\gamma_{\rm d}^{\rm LV}(T_{\rm d}) = \gamma_{\rm f}^{\rm LV}(T_{\rm f}) = \gamma^{\rm LV}(T_{\rm d}, T_{\rm f}). \tag{3}$$

With Eq. (2) then follows

$$\begin{aligned} \gamma_{\mathrm{f}}^{\mathrm{SV}}(T_{\mathrm{f}}) - \gamma_{\mathrm{d}}^{\mathrm{SV}}(T_{\mathrm{d}}) &= \gamma^{\mathrm{LV}}(T_{\mathrm{f}}, T_{\mathrm{d}}) \big[\cos \Theta_{\mathrm{f}} - \cos \Theta_{\mathrm{d}} \big] \\ &+ \gamma_{\mathrm{f}}^{\mathrm{SL}}(T_{\mathrm{f}}) - \gamma_{\mathrm{d}}^{\mathrm{SL}}(T_{\mathrm{d}}) \,. \end{aligned}$$

If we select $T_{\rm d}$ and $T_{\rm f}$ arbitrarily close to $T_{\rm S}^{\rm SV}$ [i.e., $T_{\rm d}(T_{\rm S}^{\rm SV})$ and $T_{\rm f}(T_{\rm S}^{\rm SV})$ in the schematic], then $\gamma_{\rm f}^{\rm SL}(T_{\rm f}) - \gamma_{\rm d}^{\rm SL}(T_{\rm d}) = 0$ if we agree, as discussed already, that there is no discontinuous change of $\gamma^{\rm SL}$ at $T_{\rm S}^{\rm SV}$. We, thus, can estimate $\Delta\gamma_{\rm f,d}^{\rm SV}(T_{\rm S}^{\rm SV}) \approx 0.02$ mN/m with $\Theta_{\rm d}=2^\circ$, $\Theta_{\rm f}\approx 0^\circ$, and $\gamma^{\rm LV}(T_{\rm f},T_{\rm d})=28$ mN/m [9]. The observed dewetting below $T_{\rm S}^{\rm SV}$ is in qualitative agreement with adsorption studies of alkanes on Langmuir

The observed dewetting below T_S^{SV} is in qualitative agreement with adsorption studies of alkanes on Langmuir monolayers which consisted of amphiphiles with their alkane chains oriented towards the air [16]. Upon loosely packed, disordered monolayers, alkanes adsorb, whereas on densely packed, condensed monolayers, barely any alkane molecules are found.

Surface freezing has been explained theoretically [17] as the result of an additional fluctuation-based entropic contribution to the excess surface free energy. The molecules are ordered homeotropically and fluctuate normal to the interface. Our findings of monolayers slightly thicker than the molecular length as well as the similarities of the chain length and temperature dependency of $T_{\rm S}^{\rm SV}-T_{\rm b}$ with those predicted by the theory and measured at alkane/air interfaces corroborate the theoretical approach. Minor discrepancies like the slightly extended temperature range ($T_{\rm S}^{\rm SV} \approx T_{\rm S}^{\rm LV}+0.5\,^{\circ}{\rm C}$) and monolayer thicknesses matching the molecular lengths at ${\rm C}_n>{\rm C}_{30}$ may be due to the different interfaces, respectively, molecular tilt. Above $T_{\rm S}^{\rm SV}$, liquid alkane films much thicker than the

Above T_s^{SV} , liquid alkane films much thicker than the molecular length are found. The thickness uniformity of these films, as well as those of the mesas at $T < T_b$, will be the subject of a different publication. Very similar mesa topologies with a tendency to height uniformity have been observed before for fatty acids [18] and explained as a consequence of the competition between short and long range forces.

Figure 5 graphically summarizes the three different wetting regimes and topologies as a function of the alkane chain length and the temperature. It is suggested that the decoupling of the phase transition temperatures of the bulk material at $T_{\rm b}$ and of the alkanes adjacent to the solid/vapor interface at $T_{\rm S}^{\rm SV}$ causes the intermediate wet-

ting regime between $T_{\rm b}$ and $T_{\rm S}^{\rm SV}$. The discontinuity of the surface energy $\gamma^{\rm SV}$ due to monolayer melting at $T_{\rm S}^{\rm SV}$ can be estimated to be very small $[\Delta \gamma^{\rm SV} (T_{\rm S}^{\rm SV}) \approx 0.02~{\rm mN/m}]$. The monolayer freezing behavior at the substrate/air interface resembles that of surface freezing at liquid bulk alkane/air interfaces. This and other experimental findings support a fluctuation-stabilized surface freezing mechanism.

We thank Wacker Siltronic GmbH Burghausen for grateful donation of the silicon wafers. The work was supported by the Deutsche Forschungsgemeinschaft through Sfb 335.

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